

<b>Notice of References Cited</b>		Application/Control No.	Applicant(s)/Patent Under Reexamination 10/772,651 SHIN ET AL.	
		Examiner	Art Unit Matthew E. Warren	2815 Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-6,133,637	10-2000	Hikita et al.	257/777
*	B	US-6,569,709	05-2003	Derderian, James M.	438/109
*	C	US-6,215,182	04-2001	Ozawa et al.	257/723
*	D	US-6,099,783	08-2000	Scranton et al.	264/272.11
*	E	US-2002/0004258	01-2002	Nakayama et al.	438/107
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

**FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
*	N	JP 63240053 A	10-1988	Japan	KONDO et al.	H01L 23/30
	O					
	P					
	Q					
	R					
	S					
	T					

**NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.